Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10654954	CHEN ET AL.
Examiner	Art Unit
Meless N Zewdu	2617

SEARCHED						
Class	Subclass	Date	Examiner			
455	127.5, 343.1-343.5, 515-517, 528, 550.1, 556.2, 560-561, 571-574	3/30/08	M.Z.			
370	311-314, 328-329, 338	3/30/08	M.Z.			
713	300, 310, 321-324	3/30/08	M.Z.			
340	7.32-7.39, 539.3, 693.3-693.4	3/30/08	M.Z.			
342	385-386	3/30/08	M.Z.			

SEARCH NOTES			
Search Notes	Date	Examiner	
Searched: US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT & IBM_TDB	3/30/08	m.z.	
Searched: broad textual search; class-subclass search; inventor search and assignee search	3/30/08	M.Z.	

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
455	127.5, 343.2, 574	3/30/08	M.Z.		
370	311, 338	3/30/08	M.Z.		

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